Search Notes



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Reexamination

Applicant(s)/Patent Under

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Art Unit

MARCOS BATISTA

2617

SEARCHED

Class	Subclass	Date	Examiner
370	376	6/4/2008	mb
370	509	6/4/2008	mb

SEARCH NOTES

Search Notes	Date	Examiner
Consulted w/ lab TA Yogesh Aggarwal	6/9/2008	mb
Consulted with Lun-Yi Lao	6/9/2008	mb
East Search	6/9/2008	mb
Inventor's Name Search	6/9/2008	mb
Consulted with Rafael Perez Gutierrez	12/17/2008	mb
Sefcheck, Gregory B.	12/17/2008	mb
Duong, Frank	12/17/2008	mb
Consulted with Rafael Perez Gutierrez	6/8/2009	mb
East Search	12/17/2008	mb

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
455	all	6/9/2009	mb
370	all	6/9/2009	mb

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